

Date: Monday, 11/Sep/2017

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| 8:45am - 9:00am | Opening session | |
| 9:00am - 10:30am | <p>Plenary session 1</p> <p>3D System Integration. An Interconnect Hierarchy driven Technology Landscape Eric Beyne imec, Belgium</p> <p>Printed stretchable electronics – enabler of unobtrusive biosignal monitoring Matti Mäntyselä Tampere University of Technology, Finland</p> | |
| 11:00am - 1:00pm | <p>Session 1: Advanced packaging and interconnects (1)</p> <p>Small Form-Factor, Liquid-Cooled SiPM Module for PET/MRI Applications Dr. Rainer Dohle¹, Thomas Rittweg², Dr. Ilaria Sacco³ 1: Micro Systems Engineering GmbH, 95180 Berg, Germany; 2: Micro Systems Engineering GmbH, ENS, 95180 Berg, Germany; 3: Institut für Technische Informatik der Universität Heidelberg, B6, 26, 68131 Mannheim</p> <p>Direct copper metallization on TGV Thru-Glass-Via) for high performance glass substrate Tsubasa Fujimura, Kotoku Inoue, Masatoshi Takayama, Sigeo Onitake Koto Electric Co.,Ltd., Japan</p> <p>Impact of the combination of a stress buffer layer and a wafer level underfill on 3D IC assembly using thermal compression bonding Fabrice F. C. Duval, Teng Wang, Giovanni Capuz, Pieter Bex, Kenneth J. Rebibis, Melina Lofrano, Erik Slescecx, Eric Beyne Imec, Belgium</p> <p>Experimental LTCC platform for millimeter-wave applications Camilla R. G. Kärfelt^{1,2}, François Gallée^{1,2}, Vincent Castel^{1,2}, Maïna Sinou¹, Pascal Coant^{1,2} 1: Institut Mines-Telecom/IMT Atlantique, France; 2: Lab-STICC UMR CNRS 6285</p> <p>Hot bar joining method for medical applications David Wagner, Kai Pitschmann, Ulrich Schumann, Sebastian Freidank, Bertram Schmidt, Markus Detert Otto-von-Guericke-Universität Magdeburg, Germany</p> <p>Fine Pitch High Bandwidth Flip Chip Package-on-Package Development Stanley Lin², Ian Hsu², Chi-Yuan Chen², NamJu Cho¹, Ming-Che Hsieh¹ 1: STATS ChipPAC Pte. Ltd., Singapore; 2: MediaTek, Inc.</p> | <p>Session 2: Printed, hybrid and flexible electronics</p> <p>Experimental Investigation on 3D Metal Interconnection for HySiF(hybrid system in flexible) Devices Using ElectroHydroDynamic (EHD) System Joon Yub Song, Yongjin Kim, Jae Hak Lee, Seung Man Kim, Sangil Lee Korea Institute of Machinery and Materials, Korea, Republic of (South Korea)</p> <p>3D printed flexible substrate with pneumatic driven electrodes for health monitoring Martin Schubert, Sabine Friedrich, Karlheinz Bock TU Dresden, Electronics Packaging Laboratory, Germany</p> <p>Optimized Adaptive Layout Technique for Hybrid System in Foil Golzar Alavi¹, Holger Sailer², Bjoern Albrecht², Christine Harendt², Joachim N.Burghartz^{1,2} 1: Institute for Nano and Microelectronic system, Stuttgart, Germany; 2: Institute for Microelectronics Stuttgart (IMS CHIPS), Stuttgart, Germany</p> <p>Additive waveguide manufacturing for optical bus couplers by aerosol jet printing using conditioned flexible substrates Lukas Lorenz¹, Krzysztof Niewegłowski¹, Klaus-Jürgen Wolter¹, Gerd-Albert Hoffmann², Ludger Overmeyer², Thomas Reitberger³, Jörg Franke³, Karlheinz Bock¹ 1: Technische Universität Dresden, Germany; 2: Leibniz Universität Hannover, Germany; 3: Friedrich Alexander Universität Erlangen-Nürnberg</p> <p>Data and Power Distribution via Printed Electronics in Aerospace Applications Daniel Grät¹, Nils Ischdonat², Martin Hedges³, Jörg Franke¹ 1: Friedrich-Alexander-University of Erlangen-Nuremberg, Germany; 2: Fraunhofer Institute for Applied Polymer Research IAP, Germany; 3: Neotech AMT – Advanced Manufacturing Technologies, Germany</p> <p>Pads and microscale vias with aerosol jet printing technique Jakub Krzemiński¹, Akhil Kanthamneni², David Wagner², Markus Detert², Bertram Schmidt², Małgorzata Jakubowska¹ 1: Warsaw Univ. of Tech. Faculty Mechatronics, Poland; 2: Otto-von-Guericke- Universität Magdeburg, Institut für Mikro- und Sensorsysteme, Germany</p> |
| 2:00pm - 3:40pm | <p>Session 3: Materials and processes (1)</p> <p>The importance of shear thinning, thixotropic and viscoelastic properties of thick film pastes to predict effects on printing performance Kathrin Reinhardt, Nancy Hofmann Fraunhofer IKTS, Germany</p> <p>Passive component development in LTCC Camilla R. G. Kärfelt^{1,2} 1: Institut Mines-Telecom/IMT Atlantique, France; 2: Lab-STICC UMR CNRS 6285</p> <p>Evaluation of Piezoelectric Parameters of Several Commercial Thick Film Capacitor Dielectrics Artem Ivanov University of Applied Sciences Landshut, Germany</p> <p>Thermal Peak Management using Organic Phase Change Materials for Latent Heat Storage in Electronic Applications Jacob Maxa, Andrej Novikov, Mathias Nowottnick Rostock University, Germany</p> <p>Solvent-free fluxing underfill film for electrical interconnection Keon-Soo Jang, Yong-Sung Eom, Kwang-Seong Choi, Hyun-Cheol Bae Electronics and Telecommunications Research Institute, Korea, Republic of (South Korea)</p> | <p>Session 4: Functional systems (actuators, sensors, photovoltaics and related) (1)</p> <p>Flexible optical waveguide-based interconnects for electro-optical system integration Krzysztof Niewegłowski, Lukas Lorenz, Sebastian Lungen, Tobias Tiedje, Karlheinz Bock Technische Universität Dresden, Germany</p> <p>TEMPERATURE MODULATED SEMICONDUCTOR GAS SENSOR UNDER HUMIDITY INTERFERENCE Lukasz Rafał Woźniak, Paweł Jan Kalinowski, Grzegorz Paweł Jasiński, Piotr Zbigniew Jasiński Gdansk University of Technology, Poland</p> <p>Distribution of relaxation times as a method of separation and identification of complex processes measured by impedance spectroscopy Justyna Bartoszek¹, Jakub Karczewski¹, Aleksander Mroziński¹, Sea-Fue Wang², Piotr Jasiński¹ 1: Gdansk University of Technology, Poland; 2: National Taipei University of Technology, Taiwan, R.O.C.</p> <p>Signal analyses of airbag sensor by side impact. Yeong K. Kim, Sojin Shin Inha University, Korea, Republic of (South Korea)</p> <p>Reliability evaluation of solder joints in electronics assemblies Enrico Galbiati SEM Communication & GESTLABS, Italy</p> |
| 4:10pm - 5:30pm | <p>Session 5: Materials and processes (2)</p> <p>Technological Innovations for the Manufacturing of Multilayer Ceramic Micro-Electro-Mechanical-Systems Steffen Ziesche Fraunhofer IKTS, Germany</p> <p>Residual Free Solder Processes for Fluxless Solder Pastes Alexander Hanss, Gordon Elger Technische Hochschule Ingolstadt, Germany</p> <p>3D printed ceramic structures based on LTCC: Materials, Processes and Characterizations Alexander Schulz¹, Ourania Menti Goudouri², Wolfgang Kollenberg², Jens Müller¹ 1: TU Ilmenau, Germany; 2: WZR Ceramic Solutions GmbH</p> <p>Multilayer thick-film ceramic for MCM with Laser Microvias Sebastian Löffler, Nico Richter, Christopher Mauermann, Angela Rebs, Dr.Günter Reppe Cicor Advanced Microelectronics & Substrates - RHe Microsystems GmbH, Germany</p> | <p>Session 6: Modeling, design test & reliability (1)</p> <p>Impact of process induced stresses in flip chip package Lei Wang^{1,2,3}, Cheng Xu¹, Liqiang Cao^{1,3}, Wenqi Zhang¹ 1: National Center for Advanced Packaging, Wuxi, China, People's Republic of; 2: Fudan university, Shanghai, China, People's Republic of; 3: Institute of Microelectronics of Chinese Academy of Sciences, Beijing, China, People's Republic of</p> <p>The influence of humidity, temperature and electrical fields on the insulating properties of power electronics housing materials Bianca Boettge, Sandy Klengel Fraunhofer Institute for Microstructure of Materials and Systems, Germany</p> <p>Investigation of the Influence of Voids on the Reliability of LED Solder Joints by Computer Tomography and Forward Voltage Measurement Christian Schwarzer¹, Dennis Fuchs², Miriam Rauer², Kurt-Juergen Lang³, Andreas Krügelstein⁴, Michael Kaloudis², Jörg Franke⁴ 1: Fraunhofer-Anwendungszentrum Ressourceneffizienz, Germany; 2: Hochschule Aschaffenburg, Germany; 3: OSRAM OS GmbH, Germany; 4: Lehrstuhl für Fertigungsautomatisierung und Produktionssystematik, Germany</p> <p>Advances in X-ray for Semicon Applications Keith Bryant, Ragnar Vaga SMART Group, United Kingdom</p> |

5:30pm
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7:00pm

Poster Session 1

Time evolution of strain distribution during ultrasonic bonding of Cu wire --- Impact of bonding temperature ---

Mamoru Sakamoto, Kenichi Nakadozono, Keiichiro Iwanabe, Tanemasa Asano
Kyushu University, Japan

High-precision picosecond laser structuring on LTCC for silicon chip assembly with high electrical contact density

Nam Gutzeit, Alexander Schulz, Tilo Welker, Christoph Wagner, Eric Schäfer, Jens Müller
Technische Universität Ilmenau, Germany

Ceramic in Board (CIB) substrate for high power applications

Ho Chieh (Jay) Yu, Jason Huang
Sentec E&E Co.,LTD, Taiwan

Optical pressure sensors for harsh environment

Jakub Somer, Frantisek Urban, Ivan Szendiuch
Brno university of Technology, Czech Republic

Investigations of temperature resistance of memory BGA components during multi-reflow processes for Circular Economy applications

Janusz Sitek¹, Marek Koscielski¹, Piotr Dawidowicz², Piotr Ciszewski², Maria Khramova³, Duc Nguyen Quang³, Sergio Martinez³
1: Tele and Radio Research Institute, Poland; 2: Semicon Sp. z o.o., Poland; 3: Blancco Technology Group IP Oy, Finland

Influence of Heating Direction on BGA Solder Balls Structure

Alexandr Otáhal, Jakub Somer, Ivan Szendiuch
Brno University of Technology, Czech Republic

Fabrication of Dry-patching Superhydrophobic Flexible Platform for HySiF (hybrid system in flexible) Applications

Yonglin Kim, Syed Asad Ali Zaidi, Jae Hak Lee, Seung Man Kim, Joon Yub Song
Korea Institute of Machinery and Materials, Korea, Republic of (South Korea)

Low-temperature Sintering Behavior of Ternary solder and Copper Powder for High-power Device Packaging

Yong-Sung EOM, Keon-Soo JANG, Ji-Hye SON, Hyun-Cheol BAE, Kwang-Seong CHOI
ETRI, Korea, Republic of (South Korea)

Enhanced Heat Spreading in LTCC Packages utilizing Thick Silver Tape in the Co-fire Process

Tilo Welker, Nam Gutzeit, Jens Müller
Technische Universität Ilmenau, Germany

The Transmittance Properties of Optical Adhesives in Humid Environmental Aging

Sanna Lahokallio, Janne Kiilunen, Laura Frisk
Trelac Ltd, Finland

High voltage WireLED powered directly by mains 230 Volts

AIT MANI ABDENACER¹, BOUILLARD BORIS¹, GASSE ADRIEN¹, VOLPERT MARION¹, SOULIER BRIGITTE¹, HENRY DAVID¹, VANDENEYNDE AURELIE¹, CHAMBION BERTRAND¹, RUEDA PAMELA², MERCIER FREDERIC², GILET PHILIPPE²
1: CEA GRENOBLE, France; 2: ALEDIA SAS, France

Preforms based diffusion soldering process to be used under conventional soldering process conditions

Haneen Daoud, Stephan Reichelt, Angela Loidolt
Pfarr Stanztechnik GmbH, Germany

Sintered Ag joints on copper lead frame TO220 by pressure sintering process with improved reliability and bonding strength

Ly May Chew, **Wolfgang Schmitt**, Jens Nachreiner, Daniel Schnee
Heraeus Deutschland GmbH & Co. KG, Germany

Date: Tuesday, 12/Sep/2017

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| <p>9:00am - 10:30am</p> | <p>Plenary session 2</p> <p>Future of Embedding and Fanout Packaging Technologies Rao Tummala Georgia Institute of Technology, United States of America</p> <p>Large scale sustainable production of graphene for real-life applications Krzysztof Koziol University of Cambridge</p> | |
| <p>10:30am - 12:30pm</p> | <p>Session 7: Materials and processes (3)</p> <p>Low temperature sintering of silver micro-particles induced by organic accelerators in epoxy-based binders Masahiro Inoue, Masaki Iida, Yoshiaki Sakaniwa Gunma University, Japan</p> <p>Solderability and Reliability Evolution of No-Clean Solder Fluxes Rodrigo Aguilar Inventec Performance Chemicals, France</p> <p>Development of Low-temperature Sintering Nano-silver Die Attach Materials for Bare Cu Application Akira Tsuno¹, Koji Sasaki², Noritsuka Mizumura² 1: Namics Europ EmbH, Germany; 2: Namics Corporation</p> <p>Development of selective conformal coating process based on advanced packaging for harsh environments Eric Cadalen, Olivier Maire, David Manteigas MBDA, France</p> <p>Are tin-rich solder alloys resistant to tin pest? Agata Skwarek¹, Piotr Zachariasz¹, Balázs Illés², Tomasz Czepe³, Grzegorz Garzel³, Krzysztof Witek¹ 1: Institute of Electron Technology, Krakow, Poland; 2: Budapest University of Technology and Economics, Department of Electronics Technology, Hungary; 3: Institute of Metallurgy and Materials Science, PAS, Krakow, Poland</p> <p>Acceleration Measurements during Reactive Bonding Processes Irina Spies¹, Axel Schumacher¹, Stephan Knappmann¹, Bastian Rheingans², Jolanta Janczak-Rusch², Lars P.H. Jeurgens² 1: Hahn-Schickard, Villingen-Schwenningen, Germany; 2: EMPA, Dübendorf, Switzerland</p> | <p>Session 8: Functional systems (actuators, sensors, photovoltaics and related) (2)</p> <p>Printed heater elements for smart sensor packages in LTCC Heike Bartsch¹, Artur Rydosz², Wojciech Maziarz², Tadeusz Pisarkiewicz², Dirk Stöpel¹, Jens Müller¹ 1: Technische Universität Ilmenau, Germany; 2: AGH University of Science and Technology</p> <p>LTCC-Based Micro Plasma Source for the Selective Treatment of Cell Cultures Michael Fischer¹, Mike Stubenrauch¹, Ady Naber², Nam Gutzeit¹, Maren Klett¹, Sukhdeep Singh¹, Andreas Schober¹, Hartmut Witte¹, Jens Müller¹ 1: Technische Universität Ilmenau, Germany; 2: Karlsruher Institut für Technologie, Germany</p> <p>LTCC Technology for Active Eddy Current Turbocharger Speed Sensors Martin Ihle¹, Steffen Ziesche¹, Paul Gierth¹, Andreas Tuor², Jonathan Tigelaar² 1: Fraunhofer IKTS, Germany; 2: JAQUET Technology Group AG, Switzerland</p> <p>Influence of various micro channels integrated in LTCC multilayer module on the thermal resistance Tomas Girasek¹, Alena Pietrikova¹, Tilo Welker², Jens Muller² 1: Technical University of Kosice, Slovak Republic; 2: Ilmenau University of Ilmenau</p> <p>Basic microfluidic elements in the LTCC structures Darbo Belavic^{1,2,3}, Andraž Bradeško^{2,5}, Kostja Makarovič^{2,3,4}, Marjan Hodnik¹, Hana Uršič² 1: HIPOT-RR c/o Jožef Stefan Institute, Slovenia; 2: Jožef Stefan Institute, Slovenia; 3: Centre of Excellence NAMASTE, Slovenia; 4: KEKO Equipment, Slovenia; 5: Jožef Stefan International Postgraduate School, Slovenia</p> <p>Comparison of an electronic noses based on the semiconducting and electrochemical gas sensors performance for an analysis of toxic gas concentration Grzegorz Jasiński, Paweł Kalinowski, Łukasz Woźniak, Piotr Jasiński Gdańsk University of Technology, Poland</p> |
| <p>2:00pm - 3:40pm</p> | <p>Session 10: Modeling, design test & reliability (2)</p> <p>Modelling the 3D-Printing Process for Electronic Packaging Chris Bailey University of Greenwich, United Kingdom</p> <p>A new method for prediction of corrosion processes in Aluminum housing materials for electronic components Sandy Klengel, Tino Stephan, Bolko Mühs-Portius Fraunhofer Institute for Microstructure of Materials and Systems IMWS</p> <p>Comparative FEM thermo-mechanical simulations for built-in reliability: surface mounted technology versus embedded technology for silicon dies Mickaël BALMONT, Isabelle BORD-MAJEK, Yves OUSTEN IMS Bordeaux, France</p> <p>Pulse stability of low ohmic thick film resistors Arkadiusz Dabrowski, Andrzej Dziedzic, Jakub Czarachowicz Wroclaw University of Science and Technology, Poland</p> <p>Reliability of Embedded Wafer Level Ball Grid Arrays in Automotive Applications Michael Novak¹, Wolfgang Grübl¹, Bernhard Schuch¹, Peter Ossimitz² 1: Continental, Germany; 2: Infineon Technologies AG</p> | <p>Session 9: Advanced packaging and interconnects (2)</p> <p>Newly Developed High Reliability Palladium Coated Cu Wire for Automotive Application Motoki Eto¹, Teruo Haibara¹, Ryo Oishi¹, Takashi Yamada¹, Tomohiro Uno², Tetsuya Oyamada² 1: Nippon Micrometal Corporation; 2: Nippon Steel & Sumitomo Metal Corporation</p> <p>In-line Metrology for Cu Pillar Applications in Interposer based Packages for 2.5D Integration Iuliana Panchenko^{1,2}, Martin Kunz³, Lothar Lehmann⁴, Tanya Atanasova⁴, Mathias Boettcher², Marcel Wieland⁴, Juergen M. Wolf² 1: Institute of Electronic Packaging Technology, TU Dresden, 01062, Dresden, Deutschland; 2: Fraunhofer Institute for Reliability and Microintegration IZM, ASSID, Ringstr. 12, 01468, Moritzburg, Deutschland; 3: NanoFocus AG, Max-Planck-Ring 48, 46049, Oberhausen, Deutschland; 4: Globalfoundries, Wilschdorfer Landstr. 101, 01109, Dresden, Deutschland</p> <p>Flip-chip bonding: how to meet the high accuracy requirements? Caroline AVRILLIER, Pascal METZGER, Jean-Stéphane MOTTET, Joseph MACHEDA SET, France</p> <p>High Efficient Mid Power Modules by Next Generation Chip Embedding Technology Kay Stefan Essig¹, CT Chiu², Jarris Kuo², Phidia Chen², Jean-Marc Yaonnou¹ 1: ASE (Europe) Inc.; 2: ASE Group, Taiwan</p> <p>Characterisation of Cu/Cu bonding using self-assembled monolayer as oxidation inhibitor Maria Lykova¹, Iuliana Panchenko^{1,2}, Marion Geidel³, Johanna Reif³, Ulrich Künzelmann³, Klaus-Dieter Lang⁴ 1: Institute of Electronic Packaging Technology (IAVT), TU Dresden, Dresden, Germany; 2: All Silicon System Integration Dresden (ASSID), Fraunhofer Institute for Reliability and Microintegration (IZM), Dresden, Germany; 3: Institute of Semiconductors and Microsystems (IHM), TU Dresden, Dresden, Germany; 4: Fraunhofer Institute for Reliability and Microintegration (IZM), Berlin, Germany</p> |
| <p>4:10pm - 5:30pm</p> | <p>Session 11: Advanced packaging and interconnects (3)</p> <p>Comparison of Microvia HDI PCBs with ACF interconnections in accelerated life testing Laura Frisk, Sanna Lahokallio, Janne Kiilunen Trellic Ltd, Finland</p> <p>In-Bi Low-Temperature SLID Bonding for piezoelectric materials Knut E Aasmundtveit¹, Trym Eggen^{1,2}, Hoang-Vu Nguyen¹ 1: University College of Southeast Norway, Norway; 2: GE Vingmed Ultrasound, Norway</p> <p>Liquid Solid Diffusion (LSD) Bonding – A novel joining technology Andreas Larsson^{1,2}, Torleif A Tollefsen³, Ole Martin Løvvik⁴, Knut E Aasmundtveit² 1: TECHNI AS, Norway; 2: University College of Southeast Norway, Norway; 3: TEGma AS, Norway; 4: SINTEF Materials and Chemistry, Norway</p> <p>Polyimide Foil Flip-Chip Direct Bonding Martin Deckert¹, Michael Thomas Lippert², Jakub Krzemiński³, Kentaroh Takagaki², Frank W. Ohl², Bertram Schmidt¹ 1: Otto von Guericke University Magdeburg, Germany; 2: Leibniz Institute for Neurobiology, Magdeburg, Germany; 3: Warsaw University of Technology, Poland</p> | <p>Session 12: Electronics components assembly and PCB solutions</p> <p>Embedded mini Heat Pipes as Thermal Solution for PCBs Jonathan Silvano de Sousa¹, Paul Fulmek², Michael Unger², Paul Haumer², Johann Nicolics² 1: AT&S AG, Austria; 2: Vienna University of Technology (TU-WIEN)</p> <p>The Mechanical Strength of Microvias in Reflow Cycling and Environmental Aging Janne Juha Matti Kiilunen, Laura Frisk Trellic Ltd, Finland</p> <p>Embedding technologies for heterogeneous integration of components in PCBs-an innovative modularisation approach with environmental impact Dionysios Manassis¹, Jakub Pawlikowski¹, Andreas Ostmann¹, Karsten Schischke¹, Thomas Krivec², Gerhard Podhradsky³, Martin Ramellow-Schneider¹, K-D. Lang⁴ 1: Fraunhofer IZM Berlin, Germany; 2: AT&S AG, Fabriksgasse 13, 8700 Leoben, Austria; 3: SPEECH, Speech Processing Solutions GmbH, Guthheil-Schoder-Gasse 8-12, 1100 Vienna, Austria; 4: Technical University of Berlin, Gustav-Meyer-Alle 25, 13355 Berlin, Germany</p> <p>Mechatronic Integrated Devices based on Ceramic Injection Molding for Power Electronics by using Active Solder Andreas Kruegelstein¹, Joerg Franke¹, Elisa Goetze², Frederik Zanger², Volker</p> |

Schulze², Magnus Rohde³

1: Friedrich-Alexander-University Erlangen-Nuremberg, Institute for Factory Automation and Production Systems, Germany; 2: Karlsruhe Institute of Technology, wbk Institute of Production Science, Germany; 3: Karlsruhe Institute of Technology, IAM Institute for Applied Materials, Germany

5:30pm

Poster Session 2

7:00pm

Development of PEB Face-Down Interconnection Process for Ultra Thin Flexible Package

Jae Hak Lee, Chung Woo Lee, Yong Jin Kim, Seung Man Kim, Jun-Yeob Song
Korea Institute of Machinery and Materials, Korea, Republic of (South Korea)

Integration of Screen-Printed Electroluminescent Matrix Displays in Smart Textile Items – Implementation and Evaluation

Artem Ivanov, Maximilian Wurzer
University of Applied Sciences Landshut, Germany

Open resonator technique for measuring thin dielectric Plate and film

Chung-Hsiung Chen, Chun-An Lu
ITRI, Taiwan

Physical reliability of textile electronics

Hartmann Hieber
ICR, Germany

High speed interfaces for chip to chip communication on interposer based integration

Andy Heinig
Fraunhofer IIS/EAS, Germany

Image approximation using B-Spline surfaces

Zbigniew Suszyński, **Robert Świta**
Koszalin Technical University, Poland

Modelling power LEDs in the COB case with thermal phenomena taken into account

Krzysztof Górecki, **Przemysław Ptak**
Gdynia Maritime University, Poland

Capacitive touch sensor

Samuel Zuk, **Alena Pietrikova**, **Igor Vehec**
Department of Technologies in Electronics, Technical University of Kosice, Slovak Republic

Ceramic packaging of PiezoMEMS devices

Darko Belavič^{1,2,3}, **Katarina Vojisavljević**², **Danjela Kuščer**²
1: HIPOT-RR c/o Jožef Stefan Institute, Slovenia; 2: Jožef Stefan Institute, Slovenia; 3: Centre of Excellence NAMASTE, Slovenia

Thick film resistive sensors based on Pr_{0.9}Sr_{0.1}CoO_{3-δ} and Sm_{0.9}Sr_{0.1}CoO_{3-δ} cobaltites for carbon monoxide and nitric oxide detection

Piotr Zachariasz, **Katarina Cvejín**, **Dorota Szwagierczak**, **Agata Stoch**
Institute of Electron Technology, Poland

TIME WINDOW BASED FEATURES EXTRACTION FROM TEMPERATURE MODULATED GAS SENSORS FOR PREDICTION OF AMMONIA CONCENTRATION

Paweł Jan Kalinowski, **Łukasz Rafał Woźniak**, **Grzegorz Paweł Jasiński**, **Piotr Zbigniew Jasiński**
Gdańsk University of Technology, Poland

Influence of operation temperature instability on gas sensor performance

Grzegorz Jasiński
Gdańsk University of Technology, Poland

Date: Wednesday, 13/Sep/2017

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| <p>9:15am - 10:00am</p> | <p>Plenary session 3</p> <p>Developing Damage Models for Solder Joints Exposed to Complex Stress States: Influence of Potting, Coating, BGA Mirroring, and Housing on Solder Joint Fatigue Craig Hillman DFR Solutions, United States of America</p> | |
| <p>10:30am - 12:30pm</p> | <p>Session 13: Materials and processes (4)</p> <p>Effect of bonding conditions on shear strength of joints at 200 °C using Sn-coated Cu particle Hiroshi Nishikawa, Xiangdong Liu Osaka University, Japan</p> <p>Mechanical properties and life time of high Pb-containing solder joints Golta Khatibi, Agnieszka Betzwar Kotas TU Wien, Austria</p> <p>Low Temperature Co-fired Ceramics; Physical and Electrical Properties as a Function of Firing Temperature. Jim Walker, Jim Henry, Ed Graddy, Barbara Adrian Ferro Electronic Materials</p> <p>Design, fabrication and experimental characterization of mixed thick/thin film thermoelectric microgenerators based on constantan/silver Mirosław Gracjan Gierczak, Joanna Prażmowska-Czajka, Andrzej Dziejczak Wrocław University of Science and Technology, Poland</p> <p>Silver sinter paste for SiC bonding with improved mechanical properties Wolfgang Schmitt, Ly May Chew, Daniel Schnee Heraeus Deutschland GmbH & Co. KG, Germany</p> <p>Benchmark Study of Screen Printable Silver Inks on a PPE Based Substrate Riikka Maria Mikkonen Tampere University of Technology, Finland</p> | <p>Session 14: Modeling, design test & reliability (3)</p> <p>A novel experimental approach to calibrating cohesive zone elements for advanced risk analysis of interface delamination in semiconductor packages Georg M. Reuther¹, Nadine Pflügler¹, Dominik Udiljak¹, Reinhard Pufall¹, Bernhard Wunderle² 1: Infineon Technologies AG, Germany; 2: Technische Universität Chemnitz, Germany</p> <p>A Combined Simulation and Optical Measurement Technique for Investigation of System Effects on Components Solder Fatigue Rainer Dudek Fraunhofer ENAS, Germany</p> <p>Influence of thermal phenomena on characteristics of components of the IGBT module Paweł Górecki, Krzysztof Górecki Gdynia Maritime University, Poland</p> <p>The combined effect of mechanical package stress and humidity on chip corrosion probability Georg Lorenz¹, Michél Simon-Najasek¹, Achim Lindner² 1: Fraunhofer IMWS, Germany; 2: Micronas GmbH, Germany</p> <p>A delamination study on metallization stacks of power semiconductors Thomas Walter, Golta Khatibi Christian Doppler Laboratory for Lifetime and Reliability of Interfaces in Complex Multi-Material Electronics, CTA, TU Vienna, Austria</p> <p>Crystal plasticity modeling of the heat affected zone of copper micro-wires Ali Mazloum-Nejadari^{1,2}, Martin Lederer³, Golta Khatibi³, Johann Nicolics² 1: Institute of sensor and actuator systems, TU Wien, Austria; 2: Institute of sensor and actuator systems, TU Wien, Austria; 3: Christian Doppler Laboratory for Lifetime and Reliability of Interfaces in Complex Multi-Material Electronic, Institute CTA, TU Wien, Austria</p> |
| <p>12:30pm - 1:00pm</p> | <p>Closing session - Awards - Advance information on ESTC 2018 and EMPC 2019</p> | |